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INFORMATION DISCLOSURE
STATEMENT BY APPLICANT
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	Complete if Known			
	Application Number	10/771,698		
	Filing Date	February 3, 2004		
	First Named Inventor	Ozgur Leonard		
	Art Unit	2195		
	Examiner Name	Wai, Eric Charles		
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U.S.PATENT DOCUMENTS			
Document Number lo.1 Number-Kind Code ^{2 (F NORM)}	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
2004/0010624 A1	01-15-2004	Garofalo et al.	
6,279,046 B1	08-21-2001	Armstrong et al.	
7,076,634 B2	07-11-2006	Lambeth et al.	
2004/0162914 A1	08-19-2004	St. Pierre et al.	
5,784,706	07-21-1998	Oberlin et al.	
7,095,738 B1	08-22-2006	Desanti	
2003/0069939 A1	04-10-2003	Russell	
6,075,938	06-13-2000	Bugnion et al.	
6,681,258 B1	01-20-2004	Ratcliff et al.	
6,633,963 B1	10-14-2003	Ellison et al.	
5,841,869	11-24-1998	Merkling et al.	
			-

	FOREIGN PATENT DOCUMENTS					
Examiner Initials*	Cite No.1	Foreign Patent Document Country Code ³ Number ⁴ Kind Code ⁵ (# known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
	ļ	WO 00/45262 A2	08-03-2000	Sun Microsystems, Inc.		
	 -					

Examiner	Date	
Signature	Considered	

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